Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/670,545	HSIEH ET AL.
Examiner	Art Unit
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SEARCHED				
Class	Subclass	Date	Examiner	
707	1, 3	11/8/2005	AWK	
705	75-76			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
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West US, JPO, EPO, IBM, Derwent	11/8/2005	AWK
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